- Four 10-Bit D/A Converters
- Programmable Settling Time of 3 μs or 9 μs Typ
- TMS320, (Q)SPI, and Microwire Compatible Serial Interface
- Internal Power-On Reset
- Low Power Consumption:
 5.5 mW, Slow Mode 5-V Supply
 3.3 mW, Slow Mode 3-V Supply
- Reference Input Buffers
- Voltage Output Range . . . 2× the Reference Input Voltage
- Monotonic Over Temperature
- Dual 2.7-V to 5.5-V Supply (Separate Digital and Analog Supplies)

description

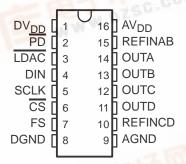
The TLV5604 is a quadruple 10-bit voltage output digital-to-analog converter (DAC) with a flexible 4-wire serial interface. The 4-wire serial interface allows glueless interface to TMS320, SPI, QSPI, and Microwire serial ports. The TLV5604 is programmed with a 16-bit serial word comprised of a DAC address, individual DAC control bits, and a 10-bit DAC value.

- Hardware Power Down (10 nA)
- Software Power Down (10 nA)
- Simultaneous Update

applications

- Battery Powered Test Instruments
- Digital Offset and Gain Adjustment
- Industrial Process Controls
- Machine and Motion Control Devices
- Communications
- Arbitrary Waveform Generation

D OR PW PACKAGE (TOP VIEW)



The device has provision for two supplies: one digital supply for the serial interface (via pins DV_{DD} and DGND), and one for the DACs, reference buffers and output buffers (via pins AV_{DD} and AGND). Each supply is independent of the other, and can be any value between 2.7 V and 5.5 V. The dual supplies allow a typical application where the DAC will be controlled via a microprocessor operating on a 3-V supply (also used on pins DV_{DD} and DGND), with the DACs operating on a 5-V supply. Of course, the digital and analog supplies can be tied together.

The resistor string output voltage is buffered by a x2 gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. A rail-to-rail output stage and a power-down mode makes it ideal for single voltage, battery based applications. The settling time of the DAC is programmable to allow the designer to optimize speed versus power dissipation. The settling time is chosen by the control bits within the 16-bit serial input string. A high-impedance buffer is integrated on the REFINAB and REFINCD terminals to reduce the need for a low source impedance drive to the terminal. REFINAB and REFINCD allow DACs A and B to have a different reference voltage then DACs C and D.

The device, implemented with a CMOS process, is available in 16-terminal SOIC and TSSOP packages. The TLV5604C is characterized for operation from 0°C to 70°C. The TLV5604I is characterized for operation from -40°C to 85°C.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



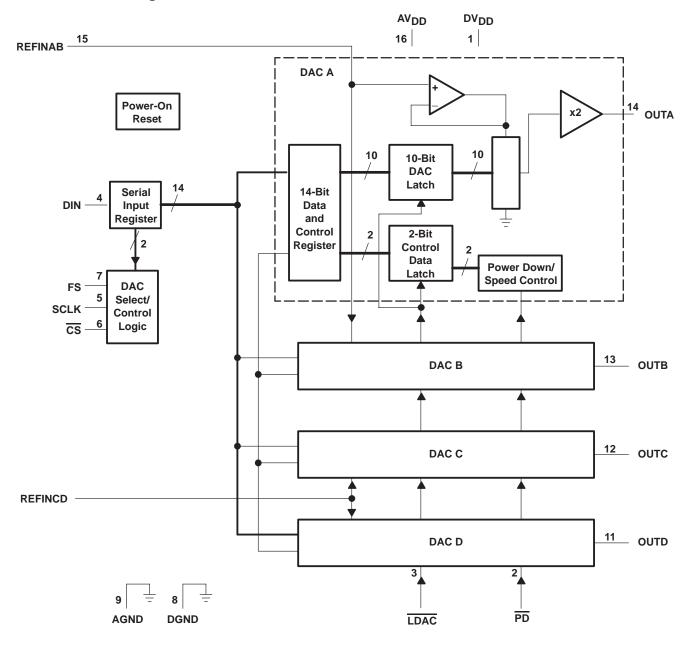
2.7-V TO 5.5-V 10-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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AVAILABLE OPTIONS

	PACKAGE						
TA	SOIC (D)	TSSOP (PW)					
0°C to 70°C	TLV5604CD	TLV5604CPW					
-40°C to 85°C	TLV5604ID	TLV5604IPW					

functional block diagram





TLV5604 2.7-V TO 5.5-V 10-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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Terminal Functions

TERMIN	IAL	1/0	DESCRIPTION
NAME	NO.	I/O	DESCRIPTION
AGND	9		Analog ground
AV_{DD}	16		Analog supply
CS	6	I	Chip select. This terminal is active low.
DGND	8		Digital ground
DIN	4	Ι	Serial data input
DV_{DD}	1		Digital supply
FS	7	I	Frame sync input. The falling edge of the frame sync pulse indicates the start of a serial data frame shifted out to the TLV5604.
PD	2	I	Power-down pin. Powers down all DACs (overriding their individual power down settings), and all output stages. This terminal is active low.
LDAC	3	I	Load DAC. When the LDAC signal is high, no DAC output updates occur when the input digital data is read into the serial interface. The DAC outputs are only updated when LDAC is low.
REFINAB	15	Ι	Voltage reference input for DACs A and B.
REFINCD	10	ı	Voltage reference input for DACs C and D.
SCLK	5	ı	Serial Clock input
OUTA	14	0	DAC A output
OUTB	13	0	DAC B output
OUTC	12	0	DAC C output
OUTD	11	0	DAC D output

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, (DV _{DD} , AV _{DD} to GND)	7 V
Supply voltage difference, (AV _{DD} to DV _{DD})	–2.8 V to 2.8 V
Digital input voltage range	0.3 V to DV _{DD} + 0.3 V
Reference input voltage range	0.3 V to AV _{DD} + 0.3 V
Operating free-air temperature range, T _A : TLV5604C	0°C to 70°C
TLV5604I	–40°C to 85°C
Storage temperature range, T _{stq}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.



TLV5604

2.7-V TO 5.5-V 10-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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recommended operating conditions

		MIN	NOM	MAX	UNIT	
Supply voltage AV DV	5-V supply	4.5	5	5.5	V	
reference voltage, V _{ref} to REFINAB, REFINCD terminal and resistance, R _L and capacitance, C _L	3-V supply	2.7	3	3.3	V	
High-level digital input, V _{IH}	$DV_{DD} = 2.7 \text{ V to } 5.5 \text{ V}$	2			V	
Low-level digital input, V _{IL}	$DV_{DD} = 2.7 \text{ V to } 5.5 \text{ V}$			0.8	V	
Peterones voltage V , to PEEINAR PEEINCD terminal	5-V supply (see Note 1)	0	2.048	AV _{DD} -1.5	V	
Reference voltage, Viet to KET INAB, KET INCD terminal	3-V supply (see Note 1)	0	1.024	AV _{DD} -1.5	V	
Load resistance, R _L		2	10		kΩ	
Load capacitance, C _L				100	pF	
Serial clock rate, SCLK				20	MHz	
Operation from air temperature	TLV5604C			70	°C	
Operating nee-an temperature	TLV5604I	-40		85	C	

NOTE 1: Voltages greater than AVDD/2 will cause output saturation for large DAC codes.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

static DAC specifications

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
	Resolution	•		10			bits	
	Integral nonlinearity (INL), end p	See Note 2			±1	LSB		
	Differential nonlinearity (DNL)		See Note 3		±0.1	±1	LSB	
EZS	Zero scale error (offset error at z	ero scale)	See Note 4			±12	mV	
	Zero scale error temperature coe	See Note 5		10		ppm/°C		
EG	Gain error		See Note 6			±0.6	%of FS voltage	
	Gain error temperature coefficient		See Note 7		10		ppm/°C	
PSRR	Dower aupply rejection ratio	Zero scale gain	See Notes 8 and 9		-80	4D		
FORK	Power supply rejection ratio	Gain	See Notes o and a		-80		dB	

- NOTES: 2. The relative accuracy or integral nonlinearity (INL) sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.
 - 3. The differential nonlinearity (DNL) sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.
 - 4. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.
 - 5. Zero-scale-error temperature coefficient is given by: EZS TC = [EZS (T_{max}) EZS (T_{min})]/V_{ref} × 10⁶/(T_{max} T_{min}).
 - 6. Gain error is the deviation from the ideal output ($2V_{ref} 1$ LSB) with an output load of 10 k Ω excluding the effects of the zero-error. 7. Gain temperature coefficient is given by: Eg TC = [Eg(T_{max}) Eg (T_{min})]/V_{ref} × 10⁶/(T_{max} T_{min}).

 - 8. Zero-scale-error rejection ratio (EZS-RR) is measured by varying the AVDD from 5 ±0.5 V and 3 ±0.5 V dc, and measuring the proportion of this signal imposed on the zero-code output voltage.
 - 9. Gain-error rejection ratio (EG-RR) is measured by varying the AVDD from 5 ±0.5 V and 3 ±0.5 V dc and measuring the proportion of this signal imposed on the full-scale output voltage after subtracting the zero scale change.



TLV5604 2.7-V TO 5.5-V 10-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

individual DAC output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
VO	Voltage output	$R_L = 10 \text{ k}\Omega$	0		AV _{DD} -0.1	V	
	Output load regulation accuracy	R_L = 2 kΩ vs 10 kΩ		0.1	0.25	% of FS voltage	

reference input (REFINAB, REFINCD)

	PARAMETER	TEST CONDITIONS	TEST CONDITIONS				
٧ _I	Input voltage range	See Note 10		0		AV _{DD} -1.5	V
R _I	Input resistance				10		MΩ
Cl	Input capacitance				5		pF
	Reference feed through	REFIN = 1 V _{pp} at 1 kHz + 1.024 V dc (see Note 11)			-75		dB
	Reference input bandwidth	PEEIN - 0.2 V	Slow		0.5		MHz
	Reference input bandwidth	REFIN = 0.2 V _{pp} + 1.024 V dc	Fast		1		IVITIZ

NOTES: 10. Reference input voltages greater than VDD/2 will cause output saturation for large DAC codes.

digital inputs (D0-D11, \overline{CS} , WEB, \overline{LDAC} , \overline{PD})

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
lн	High-level digital input current	$V_I = DV_{DD}$			±1	μΑ
I _I L	Low-level digital input current	V _I = 0 V			±1	μΑ
CI	Input capacitance			3		pF

power supply

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
		5-V supply, No load, Clock running	Slow	1.4		2.2	mA
I _{DD}	Dower aupply ourrent	3-V Supply, No load, Clock fullling	Fast		3.5	5.5	ША
	Power supply current	2 Vaupply No load Clock rupping	Slow		1	1.5	m ^
		3-V supply, No load, Clock running	Fast		3	4.5	mA
	Power down supply current, See Figure 12				10		nA



^{11.} Reference feedthrough is measured at the DAC output with an input code = 000 hex and a V_{ref(REFINAB or REFINCD)} input = 1.024 Vdc + 1 V_{pp} at 1 kHz.

TLV5604

2.7-V TO 5.5-V 10-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

analog output dynamic performance

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
SR	Output alow rate	$C_L = 100 \text{ pF}, R_L = 10 \text{ k}\Omega,$	Fast		5		V/μs
SK	Output slew rate	V _O = 10% to 90%, V _{ref} = 2.048 V, 1024 V	Slow		1		V/μs
	Output a attling time	To ± 0.5 LSB, $C_L = 100$ pF,	Fast		2.5	4	
t _S	Output settling time	$R_L = 10 \text{ k}\Omega$, See Notes 12 and 14	Slow		8.5	18	μs
	Output settling time, code to code	To ± 0.5 LSB, $C_L = 100$ pF,	Fast		1		
ts(c)	Output settiing time, code to code	$R_L = 10 \text{ k}\Omega$, See Note 13	Slow		2		μs
	Glitch energy	Code transition from 7FF to 800			10		nV-sec
SNR	Signal-to-noise ratio	Sinewave generated by DAC,			68		
S/(N+D)	Signal to noise + distortion	Reference voltage = 1.024 at 3 V and 2. $f_S = 400 \text{ KSPS}$.	.048 at 5 V,		65		
THD	Total harmonic Distortion	f _{OUT} = 1.1 kHz sinewave,			-68	Ī	dB
SFDR	Spurious free dynamic range	$C_L = 100 \text{ pF}, \qquad R_L = 10 \text{ k}\Omega,$ BW = 20 kHz			70		

NOTES: 12. Settling time is the time for the output signal to remain within \pm 0.5LSB of the final measured value for a digital input code change of 020 hex to 3FF hex or 3FF hex to 020 hex.



^{13.} Settling time is the time for the output signal to remain within \pm 0.5LSB of the final measured value for a digital input code change of one count, 1FF hex to 200 hex.

^{14.} Limits are ensured by design and characterization, but are not production tested.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

digital input timing requirements

		MIN	NOM	MAX	UNIT
t _{su(CS-FS)}	Setup time, CS low before FS↓	10			ns
t _{su} (FS–CK)	Setup time, FS low before first negative SCLK edge	8			ns
tsu(C16–FS)	Setup time, sixteenth negative edge after FS low on which bit D0 is sampled before rising edge of FS	10			ns
t _{su(C16-CS)}	Setup time, sixteenth positive SCLK edge (first positive after D0 is sampled) before \overline{CS} rising edge. If FS is used instead of the sixteenth positive edge to update the DAC, then the setup time is between the FS rising edge and \overline{CS} rising edge.	10			ns
t _{wH}	Pulse duration, SCLK high	25			ns
t _W L	Pulse duration, SCLK low	25			ns
t _{su(D)}	Setup time, data ready before SCLK falling edge	8			ns
t _{h(D)}	Hold time, data held valid after SCLK falling edge	5			ns
twH(FS)	Pulse duration, FS high	20			ns

PARAMETER MEASUREMENT INFORMATION

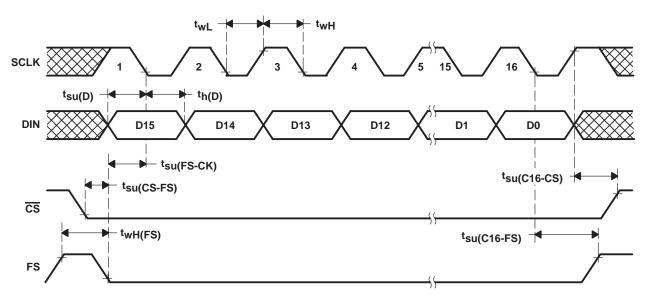


Figure 1. Timing Diagram

LOAD REGULATION 0.35 $V_{DD} = 5 V$ $V_{REF} = 2 V$ 0.30 V_O = Full Scale 0.25 Vo - Output Voltage - V 5 V Slow Mode, Sink 0.20 5 V Fast Mode, Sink 0.15 0.10 0.05 0.02 0.04 0.1 0.2 Load Current - mA

Figure 2

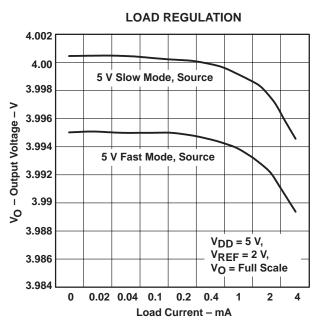


Figure 4

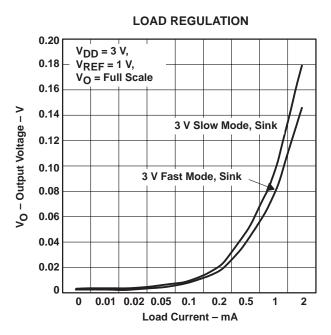


Figure 3

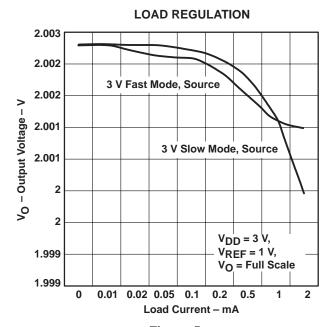
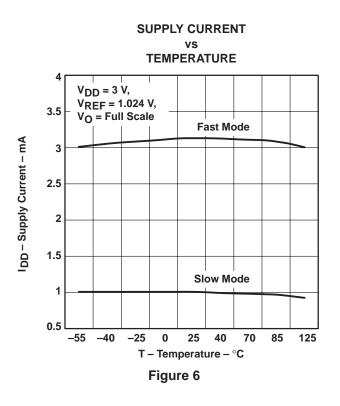
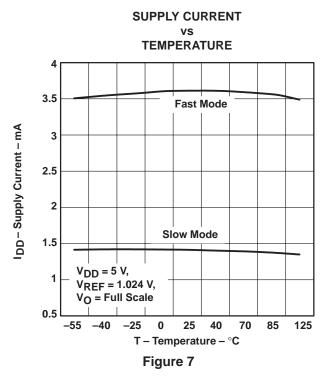
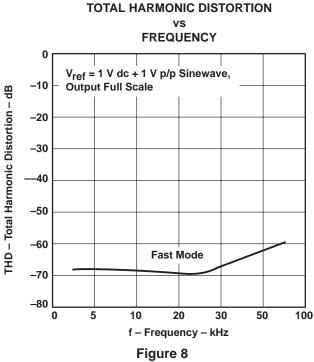


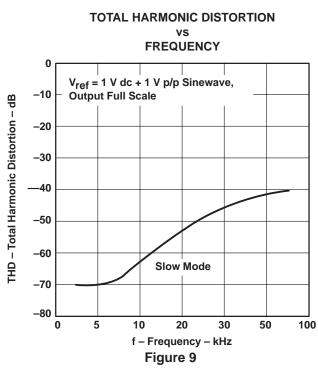
Figure 5











TOTAL HARMONIC DISTORTION AND NOISE

vs **FREQUENCY** THD - Total Harmonic Distortion And Noise - dB $V_{ref} = 1 V dc + 1 V p/p Sinewave,$ -10 Output Full Scale -20 -30--40 -50 **Fast Mode** -60 -70 -80 5 20 50 100 f - Frequency - kHz Figure 10

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TOTAL HARMONIC DISTORTION AND NOISE

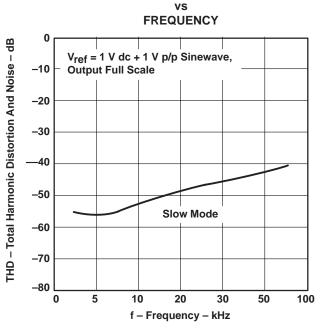


Figure 11

SUPPLY CURRENT

TIME (WHEN ENTERING POWER-DOWN MODE) 4000 3500 3000 IDD - Supply Current - µA 2500 2000 1500 1000 500 0 200 400 800 1000 t - Time - ns





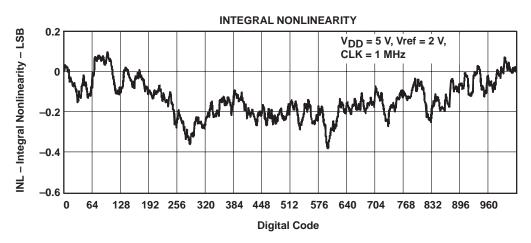


Figure 13

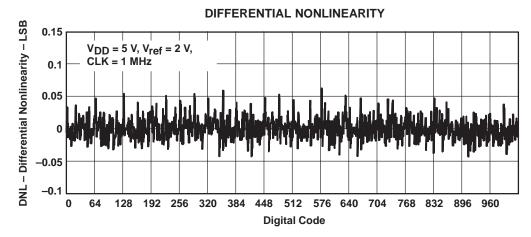


Figure 14



2.7-V TO 5.5-V 10-BIT $3\text{-}\mu\text{S}$ QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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APPLICATION INFORMATION

general function

The TLV5604 is a 10-bit single supply DAC based on a resistor string architecture. The device consists of a serial interface, speed and power-down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) is given by:

2 REF
$$\frac{\text{CODE}}{0\text{x}1000}$$
 [V]

Where REF is the reference voltage and CODE is the digital input value within the range of 0x000 to 0xFFF. A power-on reset initially resets the internal latches to a defined state (all bits zero).

serial interface

Explanation of data transfer: First, the device has to be enabled with \overline{CS} set to low. Then, a falling edge of FS starts shifting the data bit-per-bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or FS rises, the content of the shift register is moved to the DAC latch, which updates the voltage output to the new level.

The serial interface of the TLV5604 can be used in two basic modes:

- Four wire (with chip select)
- Three wire (without chip select)

Using chip select (four wire mode), it is possible to have more than one device connected to the serial port of the data source (DSP or microcontroller). The interface is compatible with the TMS320 family. Figure 15 shows an example with two TLV5604s connected directly to a TMS320 DSP.

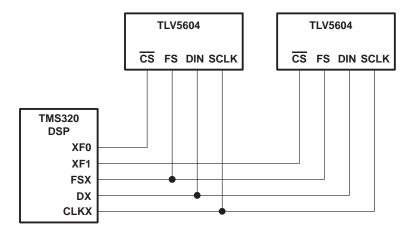


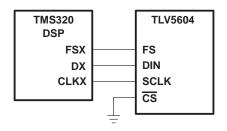
Figure 15. TMS320 Interface

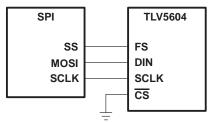


APPLICATION INFORMATION

serial interface (continued)

If there is no need to have more than one device on the serial bus, then \overline{CS} can be tied low. Figure 16 shows an example of how to connect the TLV5604 to a TMS320, SPI, or Microwire port using only three pins.





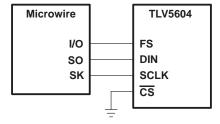


Figure 16. Three-Wire Interface

Notes on SPI and Microwire: Before the controller starts the data transfer, the software has to generate a falling edge on the I/O pin connected to FS. If the word width is 8 bits (SPI and Microwire), two write operations must be performed to program the TLV5604. After the write operation(s), the DAC output is updated automatically on the sixteenth positive clock edge.

serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{SCLKmax} = \frac{1}{t_{wH(min)} + t_{wL(min)}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{UPDATEmax} = \frac{1}{16 \left(t_{WH(min)} + t_{WL(min)}\right)} = 1.25 \text{ MHz}$$

Note that the maximum update rate is a theoretical value for the serial interface since the settling time of the TLV5604 has to be considered also.

data format

The 16-bit data word for the TLV5604 consists of two parts:

• Control bits (D15...D12)

New DAC value (D11 . . . D0)

	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
I	A1	A0	PWR	SPD		New DAC value (12 bits)						Х	Х			

X: don't care

SPD: Speed control bit. $1 \rightarrow \text{fast mode}$ $0 \rightarrow \text{slow mode}$ PWR: Power control bit. $1 \rightarrow \text{power down}$ $0 \rightarrow \text{normal operation}$



2.7-V TO 5.5-V 10-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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APPLICATION INFORMATION

In power down mode, all amplifiers within the TLV5604 are disabled. A particular DAC (A, B, C, D) of the TLV5604 is selected by A1 and A0 within the input word.

A1	A0	DAC
0	0	А
0	1	В
1	0	С
1	1	D

TLV5604 interfaced to TMS320C203 DSP

Hardware interfacing

Figure 17 shows an example of how to connect the TLV5604 to a TMS320C203 DSP. The serial port is configured in burst mode, with FSX generated by the TMS320C203 to provide the Frame Sync (FS) input to the TLV5604. Data is transmitted on the DX line, with the serial clock input on the CLKX line. The general-purpose input/output port bits IO0 and IO1 are used to generate the Chip Select (\overline{CS}) and DAC Latch Update (\overline{LDAC}) inputs to the TLV5604. The active low Power Down (\overline{PD}) is pulled high all the time to ensure the DACs are enabled.

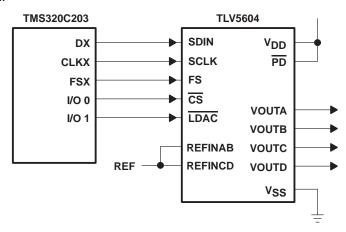


Figure 17. TLV5604 Interfaced with TMS320C203

Software

The application example generates a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and it is quadrature (cosine) signal as the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses LDAC low to update all 4 DACs simultaneously, then fetches and writes the next sample to all 4 DACs. The samples are stored in a look-up table, which describes two full periods of a sine wave.

The synchronous serial port of the DSP is used in burst mode. In this mode, the processor generates an FS pulse preceding the MSB of every data word. If multiple, contiguous words are transmitted, a violation of the tsu(C16-FS) timing requirement will occur. To avoid this, the program waits until the transmission of the previous word has been completed.



```
; Processor: TMS320C203 runnning at 40 MHz;
; Description:
; This program generates a differential in-phase (sine) on (OUTA-OUTB) and it's
; quadrature (cosine) as a differential signal on (OUTC-OUTD).
; The DAC codes for the signal samples are stored as a table of 64 12-bit values,
; describing 2 periods of a sine function. A rolling pointer is used to address the
; table location in the first period of this waveform, from which the DAC A samples are
; read. The samples for the other 3 DACs are read at an offset to this rolling pointer:
; DAC
        Function Offset from rolling pointer;
         sine
  A
  В
        inverse sine
                          16
  C
         cosine
                          8
                            24
  D
        inverse cosine
; The on-chip timer is used to generate interrupts at a fixed rate. The interrupt
; service routine first pulses LDAC low to update all DACs simultaneously with the ; values which were written to them in the previous interrupt. Then all 4 DAC values are
; fetched and written out through the synchronous serial interface. Finally, the
; rolling pointer is incremented to address the next sample, ready for the next
; interrupt.
; © 1998, Texas Instruments Incorporated
;-----;
; -----I/O and memory mapped regs ------
           .include "regs.asm"
 ----jump vectors----
           .ps Oh
           b
                 start
           b
                 int1
                 int23
           b
               timer_isr
           b
         ----- variables ------
temp
              .equ
                        0060h
                 .equ
r_ptr
                        0061
iosr_stat
                .equ
                        0062h
                 .equ
DACa_ptr
                        0063h
DACb_ptr
                 .equ
                        0064h
                 .equ
                        0065h
DACc_ptr
DACd_ptr
                 .equ
                        0066h
;----- constants ------
; DAC control bits to be OR'ed onto data
; all fast mode
DACa_control
                 .equ
                        01000h
DACb_control
                      05000h
                 .equ
                 .equ
DACc_control
                        09000h
                 .equ
DACd_control
                      0d000h
;----- tables -----
     .ds
             02000h
sinevals
              00800h
      .word
      .word
              0097Ch
      .word
              00AE9h
      .word
              00C3Ah
      .word
              00D61h
      .word
              00E53h
      .word
              00F07h
              00F76h
      .word
              00F9Ch
              00F76h
      .word
      .word
              00F07h
      .word
              00E53h
              00D61h
      .word
      .word
              00C3Ah
```



; disable interrupts ;-----setc INTM

```
APPLICATION INFORMATION
               00AE9h
      .word
      .word
               0097Ch
               00800h
      .word
      .word
               00684h
               00517h
      .word
      .word
               003C6h
      .word
               0029Fh
      .word
               001ADh
      .word
               000F9h
               0008Ah
      .word
               00064h
      .word
      .word
               0008Ah
               000F9h
      .word
      .word
               001ADh
      .word
               0029Fh
      .word
               003C6h
      .word
               00517h
               00684h
      .word
      .word
               00800h
      .word
               0097Ch
      .word
               00AE9h
      .word
               00C3Ah
               00D61h
      .word
      .word
               00E53h
      .word
               00F07h
      .word
               00F76h
      .word
               00F9Ch
      .word
               00F76h
      .word
               00F07h
              00E53h
      .word
      .word
               00D61h
               00C3Ah
      .word
               00AE9h
      .word
      .word
               0097Ch
      .word
               00800h
      .word
               00684h
               00517h
      .word
      .word
               003C6h
      .word
               0029Fh
      .word
               001ADh
      .word
               000F9h
               0008Ah
      .word
               00064h
      .word
               0008Ah
      .word
      .word
               000F9h
      .word
               001ADh
               0029Fh
      .word
      .word
               003C6h
      .word
               00517h
      .word
              00684h
; Main Program
;------
      .ps
          1000h
      .entry
start
```



; disable maskable interrupts

splk #0ffffh, IFR; clear all interrupts splk #0004h, IMR; timer interrupts unmasked

```
set up the timer
 timer period set by values in PRD and TDDR
 period = (CLKOUT1 period) \times (1+PRD) \times (1+TDDR)
  examples for TMS320C203 with 40 MHz main clock
           TDDR
                   PRD
24 (18h)
39 (27h)
; Timer rate
 80 kHz
   50 kHz
                       39 (27h)
prd_val.equ
                0018h
tcr_val.equ 0029h
     splk
           #0000h, temp
                       ; clear timer
     out
           temp, TIM
           #prd_val, temp ; set PRD
     splk
     out
           temp, PRD
           #tcr_val, temp ; set TDDR, and TRB=1 for auto-reload
     splk
     out
          temp, TCR
; Configure IOO/1 as outputs to be :
; IOO CS
          - and set high
; IO1 LDAC
          - and set high
;-----
     in
          temp, ASPCR ; configure as output
     lacl temp
     or
           #0003h
     sacl
          temp
           temp, ASPCR
     out
           temp, IOSR
                     ; set them high
     in
     lacl
          temp
     or
           #0003h
     sacl
           temp
     out
           temp, IOSR
; set up serial port for
; SSPCR.TXM=1 Transmit mode - generate FSX
; SSPCR.MCM=1
             Clock mode - internal clock source
; SSPCR.FSM=1 Burst mode
     splk #0000Eh, temp
     out
           temp, SSPCR
                     ; reset transmitter
     splk #0002Eh, temp
     out temp, SSPCR
; reset the rolling pointer
    lacl #000h saclr_ptr
; enable interrupts
  clrc INTM
; enable maskable interrupts
; loop forever!
;------
      idle
                  ; wait for interrupt
       b next
:-----
; all else fails stop here
done b done ; hang there
```



2.7-V TO 5.5-V 10-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
; Interrupt Service Routines
;-----
int1 ret ; do nothing and return
int23
       ret ; do nothing and return
timer_isr:
     in
           iosr_stat, IOSR ; store IOSR value into variable space
     #0FFFDh
     and
                        ; reset IO1 - LDAC low
     sacl temp
         temp, IOSR;
     out
           #0002h
                       ; set IO1 - LDAC high
     or
     sacl temp
     out temp, IOSR
     and #0FFFEh
                       ; reset IOO - CS low
     sacl temp
     out temp, IOSR
     lacl r_ptr
                         ; load rolling pointer to accumulator
     add
           #sinevals
                         ; add pointer to table start
     sacl DACa_ptr
                         ; to get a pointer for next DAC a sample
     add
           #08h
                         ; add 8 to get to DAC C pointer
     sacl DACc_ptr
                          ; add 8 to get to DAC B pointer
     add
          #08h
          DACb_ptr
     sacl
     add #08h
                          ; add 8 to get to DAC D pointer
     sacl DACd_ptr
     mar *,ar0
                          ; set ar0 as current AR
     ; DAC A
              ar0, DACa_ptr; ar0 points to DAC a sample
              * ; get DAC a sample into accumulator
     lacl
             #DACa_control; OR in DAC A control bits
     sacl
              temp
              temp, SDTR ; send data
; We must wait for transmission to complete before writing next word to the SDTR.
; TLV5604 interface does not allow the use of burst mode with the full packet rate, as
; we need a CLKX -ve edge to clock in last bit before FS goes high again, to allow SPI
; compatibility.
             #016h
                       ; wait long enough for this configuration
     rpt
                          ; of MCLK/CLKOUT1 rate
     nop
     ; DAC B
     lar
              ar0, DACb_ptr; ar0 points to DAC a sample
              * ; get DAC a sample into accumulator
     lacl
              #DACb_control; OR in DAC B control bits
     or
     sacl
              temp
                        ; send data
              temp, SDTR
     out
             #016h ; wait long enough for this configuration
     rpt
                         ; of MCLK/CLKOUT1 rate
     nop
```



TLV5604 2.7-V TO 5.5-V 10-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
; DAC C
              ar0, DACc_ptr; ar0 points to DAC a sample
     lar
     lacl
                         ; get DAC a sample into accumulator
              #DACc_control; OR in DAC C control bits
     or
     sacl
              temp
              temp, SDTR
                         ; send data
     Out
                         ; wait long enough for this configuration
              #016h
     rpt
     nop
                          ; of MCLK/CLKOUT1 rate
  ; DAC D
  lar
              ar0, DACd_ptr; ar0 points to DAC a sample
              * ; get DAC a sample into accumulator
  lacl
              #DACd_control; OR in DAC D control bits
  or
  sacl
  out
              temp, SDTR
                         ; send data
                         ; load rolling pointer to accumulator
  lacl
             r_ptr
              #1h
                         ; increment rolling pointer
  add
  and
              #001Fh
                         ; count 0-31 then wrap back round
              r_ptr
                         ; store rolling pointer
  sacl
  rpt
              #016h
                          ; wait long enough for this configuration
  nop
                          ; of MCLK/CLKOUT1 rate
  ; now take CS high again
              lacl
              #0001h
                          ; set IOO - CS high
  or
             temp
  sacl
                          ;
             temp, IOSR
  out
  clrc
             intm
                         ; re-enable interrupts
  ret
                          ; return from interrupt
.end
```



APPLICATION INFORMATION

TLV5604 interfaced to MCS®51 microcontroller

hardware interfacing

Figure 18 shows an example of how to connect the TLV5604 to an MCS $^{\circledR}$ 51 Microcontroller. The serial DAC input data and external control signals are sent via I/O Port 3 of the controller. The serial data is sent on the RxD line, with the serial clock output on the TxD line. Port 3 bits 3, 4, and 5 are configured as outputs to provide the DAC latch update ($\overline{\text{LDAC}}$), chip select ($\overline{\text{CS}}$) and frame sync (FS) signals for the TLV5604. The active low power down pin ($\overline{\text{PD}}$) of the TLV5604 is pulled high to ensure that the DACs are enabled.

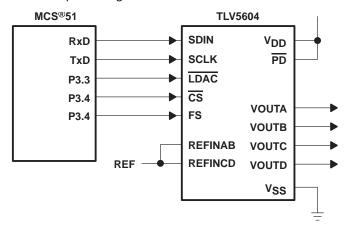


Figure 18. TLV5604 Interfaced with MCS[®]51

software

The example is the same as for the TMS320C203 in this datasheet, but adapted for a MCS®51 controller. It generates a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and it's quadrature (cosine) signal as the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses LDAC low to update all 4 DACs simultaneously, then fetches and writes the next sample to all 4 DACs. The samples are stored as a look-up table, which describes one full period of a sine wave.

The serial port of the controller is used in Mode 0, which transmits 8 bits of data on RxD, accompanied by a synchronous clock on TxD. Two writes concatenated together are required to write a complete word to the TLV5604. The $\overline{\text{CS}}$ and FS signals are provided in the required fashion through control of IO port 3, which has bit addressable outputs.





```
; Processor: 80C51
; Description:
; This program generates a differential in-phase (sine) on (OUTA-OUTB) and it's
; quadrature (cosine) as a differential signal on (OUTC-OUTD).
; © 1998, Texas Instruments Incorporated
          GENIO
   MAIN
                      CODE
             SEGMENT
   ISR
             SEGMENT
                       CODE
                      CODE
   SINTBL
             SEGMENT
          SEGMENT DATA
SEGMENT IDATA
   VAR1
   STACK
; Code start at address 0, jump to start
             CSEG AT 0
             LJMP start
                              ; Execution starts at address 0 on power-up.
; Code in the timerO interrupt vector
;______
           CSEG AT 0BH
             LJMP timer0isr; Jump vector for timer 0 interrupt is 000Bh
; Global variables need space allocated
;-----
             RSEG VAR1
                         1
1
             DS
DS
Temp_ptr:
rolling_ptr:
; Interrupt service routine for timer 0 interrupts
             RSEG ISR
timer0isr:
             PUSH
                    PSW
             PUSH ACC
             CLR
                    INT1
                             ; pulse LDAC low
             SETB INT1
                             ; to latch all 4 previous values at the same time
                              ; 1st thing done in timer isr => fixed period
                   T0
                              ; set CS low
   ; The signal to be output on each DAC is a sine function.
   ; One cycle of a sine wave is held in a table @ sinevals as 32 samples of msb,
   ; lsb pairs (64 bytes). We have one pointer which rolls round this table,
   ; rolling_ptr, incrementing by 2 bytes (1 sample) on each interrupt (at the end of
   ; this routine).
   ; The DAC samples are read at an offset to this rolling pointer:
   ; DAC Function Offset from rolling_ptr
     Α
          sine
                              0
   ; B
          inverse sine
                              32
                             16
48
     C
          cosine
   ; D
          inverse cosine
         DPTR, #sinevals ; set DPTR to the start of the table of sine signal values R7,rolling_ptr ; R7 holds the pointer into the sine table A,R7 ; get DAC A msb ; msb of DAC A is in the ACC
   MOV
   MOV
   VOM
   MOVC
        A,@A+DPTR
                             ; transmit it - set FS low
; send it out the serial port
; increment the pointer in R7
   CLR
         т1
   MOV
          SBUF,A
         R7
   INC
          A,R7
                             ; to get the next byte from the table ; which is the lsb of this sample, now in ACC
   VOM
        A,@A+DPTR
   MOVC
```



2.7-V TO 5.5-V 10-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
A_MSB_TX:
   JNB
         TI, A_MSB_TX ; wait for transmit to complete
                       ; clear for new transmit
   CLR
         TT
   MOV
         SBUF,A
                      ; and send out the 1sb of DAC A
   ; DAC C next
   ; DAC C codes should be taken from 16 bytes (8 samples) further on in the sine table
   ; - this gives a cosine function
   MOV
                       ; pointer in R7
         A,#0FH
                       ; add 15 - already done one INC
   ADD
                      ; wrap back round to 0 if > 64
   ANL
         A,#03FH
   MOV
         R7,A
                       ; pointer back in R7
   MOVC
        A,@A+DPTR
                      ; get DAC C msb from the table
         A,#01H
                       ; set control bits to DAC C address
   ORL
A LSB TX:
         TI,A_LSB_TX ; wait for DAC A lsb transmit to complete
   JINB
   SETB
                       ; toggle FS
   CLR
         Т1
   CLR
         TΙ
                       ; clear for new transmit
   MOV
         SBUF,A
                       ; and send out the msb of DAC C
   TNC
                       ; increment the pointer in R7
   MOV
         A,R7
                       ; to get the next byte from the table
         A,@A+DPTR
                      ; which is the lsb of this sample, now in ACC
   MOVC
C_MSB_TX:
         TI,C_MSB_TX ; wait for transmit to complete
   JNB
   CLR
                       ; clear for new transmit
         TT
   MOV
                       ; and send out the lsb of DAC C
         SBUF, A
   ; DAC B next
   ; DAC B codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives an inverted sine function
                       ; pointer in R7
   VOM
         A,R7
         A,#0FH
                       ; add 15 - already done one INC
   ADD
         A,#03FH
   ANL
                       ; wrap back round to 0 if > 64
   MOV
         R7,A
                       ; pointer back in R7
   MOVC
        A,@A+DPTR
                       ; get DAC B msb from the table
   ORL
         A,#02H
                       ; set control bits to DAC B address
C_LSB_TX:
   JNB
         TI,C_LSB_TX
                              ; wait for DAC C lsb transmit to complete
   SETB
                              ; toggle FS
   CLR
   CLR
         ΤТ
                             ; clear for new transmit
   MOV
                              ; and send out the msb of DAC B
         SBUF,A
                             ; get DAC B LSB
                             ; increment the pointer in R7
   INC
   VOM
         A,R7
                              ; to get the next byte from the table
                              ; which is the lsb of this sample, now in ACC
   MOVC
         A,@A+DPTR
B MSB TX:
   JNB
         TI,B_MSB_TX
                             ; wait for transmit to complete
   CLR
         ТT
                             ; clear for new transmit
   VOM
         SBUF,A
                             ; and send out the 1sb of DAC B
```



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```
; DAC D next
   ; DAC D codes should be taken from 16 bytes (8 samples) further on in the sine table
   ; - this gives an inverted cosine function
   MOV
        A,R7
                           ; pointer in R7
       A,#0FH
                           ; add 15 - already done one INC
   ADD
   ANL
       A,#03FH
                           ; wrap back round to 0 if > 64
   MOV
       R7,A
                            ; pointer back in R7
   MOVC A,@A+DPTR
                           ; get DAC D msb from the table
   ORL
         A,#03H
                            ; set control bits to DAC D address
B_LSB_TX:
   JNB
                            ; wait for DAC B lsb transmit to complete
         TI,B_LSB_TX
   SETB T1
                            ; toggle FS
   CLR
       Т1
   CLR
        TΙ
                            ; clear for new transmit
   MOV SBUF, A
                            ; and send out the msb of DAC D
                           ; increment the pointer in R7
   INC
   MOV
                            ; to get the next byte from the table
         A,R7
   MOVC A,@A+DPTR
                            ; which is the lsb of this sample, now in ACC
D_MSB_TX:
                            ; wait for transmit to complete
   JNB
         TI,D_MSB_TX
                            ; clear for new transmit
   CLR
         TI
   MOV
         SBUF,A
                            ; and send out the 1sb of DAC D
   ; increment the rolling pointer to point to the next sample
   ; ready for the next interrupt
        A,rolling_ptr
                           ; add 2 to the rolling pointer
   ADD
       A,#02H
   ANL
       A,#03FH
                           ; wrap back round to 0 if > 64
                           ; store in memory again
   VOM
       rolling_ptr,A
D_LSB_TX:
   JNBTI,D_LSB_TX
                           ; wait for DAC D lsb transmit to complete
   CLR
                            ; clear for next transmit
   SETB T1
                            ; FS high
   SETB T0
                            ; CS high
   POP
       ACC
   POP
       PSW
; Stack needs definition
      RSEG STACK
      DS
            10h
                           ; 16 Byte Stack!
```



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2.7-V TO 5.5-V 10-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
; Main program code
     RSEG MAIN
start:
     MOV
          SP,#STACK-1
                          ; first set Stack Pointer
      CLR
                       ; set serial port 0 to mode 0 ; set timer 0 to mode 2 - auto-reload
           SCON, A
      MOV
      MOV
           TMOD, #02H
           TH0, #038H
                          ; set THO for 5 kHs interrupts
      MOV
      SETB
           INT1
                          ; set LDAC = 1
      SETB T1
                           ; set FS = 1
      SETB T0
                           ; set CS = 1
                       ; enable timer 0 interrupts
      SETB ET0
      SETB EA
                          ; enable all interrupts
      VOM
           rolling_ptr,A ; set rolling pointer to 0
      SETB
           TR0
                          ; start timer 0
always:
     JMP always
                        ; while(1) !
; Table of 32 sine wave samples used as DAC data
;------
      RSEG SINTBL
sinevals:
              01000H
     DW
              0903EH
      DW
              05097н
      DW
      DW
              0305CH
              0В086Н
      DW
      DW
              070CAH
      DW
              OFOEOH
      DW
              OF06EH
      DW
              0F039H
              0F06EH
      DW
      DW
              OFOEOH
              070CAH
      DW
              0B086H
      DW
      DW
              0305CH
      DW
              05097н
      DW
              0903EH
      DW
              01000H
      DW
              06021H
      DW
              0A0E8H
      DW
              0C063H
      DW
              040F9H
      DW
              080B5H
              0009FH
      DW
      DW
              00051H
      DW
              00026H
      DW
              00051H
               0009FH
      DW
              080B5H
      DW
      DW
              040F9H
              0C063H
      DW
              0A0E8H
      DW
              06021H
END
```

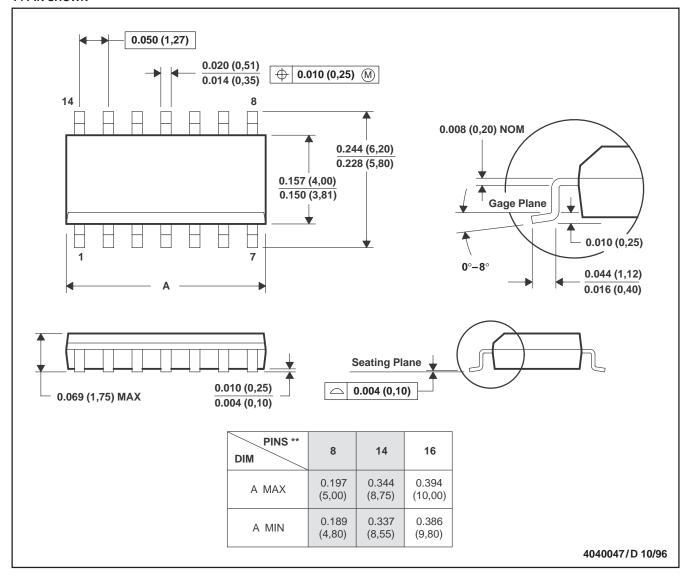


MECHANICAL DATA

D (R-PDSO-G**)

14 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012



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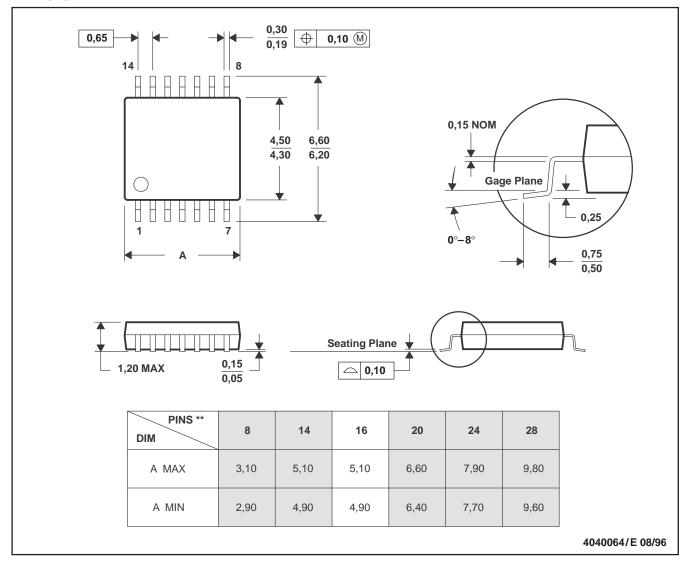
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MECHANICAL DATA

PW (R-PDSO-G**)

14 PIN SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



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